**Electronic Supplementary Information (ESI):** 

## Facile synthesis of freestanding Si nanowire arrays by one-step template-free molten salt electro-deoxidation of SiO<sub>2</sub>

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## **Experimental details**

In a typical synthesis process, 220 g CaCl<sub>2</sub> (analytical reagent, Sinopharm, China) was used for the electrolytic bath. It was dried in a muffle furnace at 150 °C for 5 hours and then 350 °C for 10 hours to remove residue water before use. A cylindrical graphite crucible (1.8 g·cm<sup>-3</sup>, 0.005% ash, JA Carbon ltd. China) was used to hold the electrochemical cell (inner height 160 mm, outer diameter 65 mm and wall thickness 7.5 mm). The graphite crucible was heated in vacuum at 180 °C for 10 hours before use. After being filled with CaCl<sub>2</sub> salt, the crucible was placed inside a quartz glass tube which was attached in a stainless steel reactor in a vertical furnace. All the

experiments were carried out under Ar atmosphere in this stainless steel reactor which was sealed by flange structure at 850 °C.

The graphite crucible was screwed on the top edge by a Mo rod (3mm in diameter, 99%, Tongli Metal Ltd. China) to serve as the counter electrode. A working electrode was composed of a quartz glass plate, 2 pieces of nickel net and 2 kinds of Mo wires. In a typical working electrode, a rectangular thin quartz glass plate (20\*10\*1 mm, 99.9% SiO<sub>2</sub>, Changda Quartz, China) was bounded with 2 pieces of Ni net (20\*10 mm 20 mesh, Shenghua Nets, China) and a folded Mo wire (1 mm in diameter, Alfa Aesar) by a small amount of Mo thin wire (0.25 mm in diameter, Alfa Aesar) to form a sandwich-like electrode. Electrical contact was formed by binding the working electrode to a 3 mm diameter Mo rod with 0.25 mm diameter Mo wire.

Electro-deoxidation experiments were performed with a Princeton Parstat 263 A potentiostat/galvanostat. Samples were prepared by electrolysis (electro-deoxidation) at a constant cell voltage in a range of 1.7 V ~ 2.2 V. When the reaction finished, the sample was cooled down in Ar atmosphere in the reactor. Later the sample was washed. Firstly rinsing was done by distilled water tenderly to remove the salt. After that, the Mo wires and Ni nets were peeled off carefully. Then the sample was washed by 0.1 mol  $L^{-1}$  hydrochloric acid until no gas emitting. At last the sample was washed with water and ethanol to remove the final residues of acid and salt. Then after filtering, the sample was dried at 60 °C and collected.

SEM images were taken on FEI Quanta 200F scanning electron microscope, with a working voltage of 20 kV. EDX accessory is Ametec Quanta 200 FEG 132-10, Detecting Unit PV7760/68ME.

X-ray diffraction (XRD) was carried out using a Rigaku Rint D/MAX-2500/PC, operated at 40 kV and 30 mA. Samples were scanned at 5 °/min 2 $\theta$  under ambient conditions.

Transmission electron microscopy (TEM) images were digitally acquired using a FEI Tecnai G2 Spirit transmission electron microscope operated at 100 kV. TEM samples were prepared by scratching a piece of Si NWAs by sharp razor blade and 10 min ultrasonic dispersion in ethanol, then drop-casting onto 200 mesh lacey carbon copper TEM grids.

HRTEM image and SAED image were acquired using FEI Tecnai G2 F30 S-Twin, operated at Accelerate Voltage of 300kV.

XPS test was done by Shimadzu Amicus XPS spectrometer. The thickness of the oxide layer was determined by comparing the relative areas of the peak at 99.4 eV (assigned to  $Si^{0}$ ) and the peak at 103.5 eV (assigned to  $Si^{4+}$ ). (See the reference cited in the text)

## Calculation of the energy cost for the Si NWAs synthesis

| Charge, C | 863 | 1259 | 1411 | 1520 | 2131 | 2159 |
|-----------|-----|------|------|------|------|------|

Origin data of Si NWAs:

| Thickness of Si NWAs, $\mu m$         | 120         | 200         | 180                     | 220           | 300          | 350               |
|---------------------------------------|-------------|-------------|-------------------------|---------------|--------------|-------------------|
| Fitting: linear                       |             |             |                         |               |              |                   |
| Y (μm) = 0.1598 X (C                  | 2) – 20.536 | i           |                         |               |              | (1)               |
| r = 0.970                             |             |             |                         |               |              |                   |
| intercept: Y=0, X                     | (= 128.5    |             |                         |               |              |                   |
| The quartz electrode are              | ea: ~ 4 cm² | (20*10*0.   | 5 quartz gl             | ass)          |              |                   |
| Thus for unit area (1 cm <sup>2</sup> | ²), the equ | ation is:   |                         |               |              |                   |
| Y (μm) = 0.6392 X (C                  | 2) –20.536  |             |                         |               |              | (2)               |
| intercept: Y=0, X                     | (= 32.1     |             |                         |               |              |                   |
| According to the equation             | ons (2),    |             |                         |               |              |                   |
| $\Delta Y = 1, \Delta X = 1/0.63$     | 392 = 1.56  | (C)         |                         |               |              |                   |
| i.e., for 1 $\mu m$ growth of s       | silicon nan | owire array | vs of 1 cm <sup>2</sup> | , the electri | city needec  | l is              |
| 1.56 C. The electricity ne            | eded for t  | he beginniı | ng of the g             | rowth is 32.  | .1 C.        |                   |
| Suppose U = 2.2V, the po              | ower for 1  | µm growtł   | n of silicon            | nanowire a    | rrays per ci | m <sup>2</sup> is |
| 1.56 C * 2.2V =                       | 3.4 J.      |             |                         |               |              |                   |
|                                       |             |             |                         |               |              |                   |
|                                       |             |             |                         |               |              |                   |



*Figure S1*. Photographs of the sandwich structured electrode.



*Figure S2*. TEM images of two fragments of Si NWAs.



*Figure S3*. (a) SEM image of one layer Si NWAs. (b) SEM image of one layer Si NWAs in side-view, showing the disordered Si layer exists on top of the wheatear-like structure of the Si NWAs. (c) Low magnification SEM image of double-layered Si NWAs in side view. (d) Higher magnification SEM image of double-layered Si NWAs, showing the boundary between the two layers.



*Figure S4*. Photographs of the pristine quartz glass (20\*10\*0.5 mm) and the as synthesized Si NWAs.



*Figure S5*. SEM images of cone-shape Si NWAs.